PATENTS

Attorney Docket No.: ELM-2 Cont. 4

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Application No.

: Glenn J. Leedy

: 10/672,961 Confirmation No.: 9439

Filed

Applicant

: September 26, 2003

For

: THREE DIMENSIONAL MULTI LAYER MEMORY AND

CONTROL LOGIC INTEGRATED CIRCUIT

STRUCTURE

Group Art Unit : 2822

Examiner

: Monica Lewis

Mail Stop AMENDMENT Commissioner for Patents P.O. Box 1450 Alexandria, Virginia 22313-1450

SUPPLEMENTAL INFORMATION DISCLOSURE STATEMENT

Sir:

In accordance with 37 C.F.R. §§ 1.56 and 1.97, applicant wishes to call the attention of the Examiner to the following documents:

Foreign Patent Documents

חבי	3233195	03/17/1983	Mitsubishi Electric
מע	3233193	03/1//1903	Corporation
JP	2037655	02/07/1990	Siemens AG
JP	3127816	05/30/1991	Canon KK
JP	3174715	07/29/1991	Fujitsu Limited
WO	98/19337	05/07/1998	Trusi Technologies,

Nonpatent Literature Documents

Wolf, Stanley and Richard N. Tauber; Silicon Processing For the VLSI Era, Volume 1: Process Technology; Sunset Beach, CA: Lattice Press, 1986, pages 191-194 05/01/2007 AWONDAF1 00000036 061075 10672961

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The aforementioned references are listed on the accompanying Form PTO/SB/08 (submitted in duplicate). Pursuant to 37 C.F.R. 1.98 (a)(2), copies of the aforementioned Foreign Patent Documents and Non-Patent Literature Documents are enclosed herewith.

Applicant reserves the right to establish the patentability of the claimed invention over any of the information provided herewith, and/or to prove that this information may not be prior art, and/or to prove that this information may not be enabling for the teachings purportedly offered.

The above-identified documents were previously cited in an Information Disclosure Statement filed on September 26, 2006, and were not considered by the Examiner. These references are being re-submitted herewith for the Examiner's consideration.

It is respectfully requested that these references be:

(1) fully considered by the Patent and Trademark Office during the examination of this application; and (2) printed on any patent which may issue on this application. Applicant requests that a copy of Form PTO-SB/08, as considered and initialed by the Examiner, be returned with the next communication.

This Statement is submitted with a Request for Continued Examination under 37 C.F.R. § 1.114. The Director is hereby authorized to charge \$180.00 in payment of the fee for submission of this Information Disclosure Statement pursuant to 37 C.F.R. §1.97(c)(2), payment of any additional fees required in connection with this Statement, or to credit any overpayment of the same, to Deposit Account No. 06-1075 (Order No.: 001202-0127). A duplicate copy of this Information Disclosure Statement is enclosed herewith.

An early and favorable action is respectfully requested.

Respectfully submitted,

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PTO/SB/08a/b (08-03)

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Substitu	ite for form 1449A/B/PT	го		Complete if Known		
				Application Number	10/672,961 (Conf. No. 9439)	
INF	ORMATION	N DIS	SCLOSURE	Filing Date	September 26, 2003	
ST	STATEMENT BY APPLICANT			First Named Inventor	Glenn J. Leedy	
				Art Unit	2822	
(Use as many sheets as necessary)		Examiner Name	Monica Lewis			
Sheet	1	of	1	Attorney Docket Number	ELM-2 CONT. 4	

	U.S. PATENT DOCUMENTS							
Examiner Initials*	Cite No.1	Document Number Number-Kind Code ² (<i>if known</i>)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear			

	FOREIGN PATENT DOCUMENTS								
Examiner	Cite	Foreign Patent Document	Publication	Name of Patentee or	Pages, Columns, Lines,				
Initials*	No.1	Country Code ³ -Number ⁴ -Kind Code ⁵ (if known)	Date MM-DD-YYYY	Applicant of Cited Document	Where Relevant Passages or Relevant Figures Appear				
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		JP3174715	07-29-1991	Fujitsu Limited					
		WO 98/19337	05-07-1998	Trusi Technologies, LLC					

		NON PATENT LITERATURE DOCUMENTS	
Examiner Initials	Cite No.1	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T ²
		Wolf, Stanley and Richard N. Tauber; Silicon Processing For the VLSI Era, Volume 1: Process Technology; Sunset Beach, CA: Lattice Press, 1986, pages 191-194	
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EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant. ¹ Applicant's unique citation designation number (optional). ² See Kinds Codes of USPTO Patent Documents at www.uspto.gov or MPEP 901.04. ³ Enter Office that issued the document, by the two-letter code (WIPO Standard ST.3). ⁴ For Japanese patent documents, the indication of the year of the reign of the Emperor must precede the serial number of the patent document. ⁵ Kind of document by the appropriate symbols as indicated on the document under WIPO Standard ST.16 if possible. ⁶ Applicant is to place a check mark here if English language Translation is attached.

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Signature	Considered	



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Sub	stitute for form 1449A/B/PT	0	*	Complete if Known		
				Application Number 10/672,961 (Conf. No. 943		
11	NFORMATION	I DI	SCLOSURE	Filing Date	September 26, 2003	
S	TATEMENT E	3Y /	APPLICANT	First Named Inventor	Glenn J. Leedy	
				Art Unit	2822	
(Use as many sheets as necessary)			s necessary)	Examiner Name	Monica Lewis	
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